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**Data Sheet**

August 2, 2026

BURLEIGH

## Burleigh WA-2000 Wavemeter Junior

The WA2000 provides a Wavemeter Junior Michelson fringe-count laser wavelength meter designed for continuous-wave sources with HeNe push-button calibration, LED display, and RS-232 remote readout, offering typical visible-band class coverage with detector options that should be confirmed on the specific unit. CW laser wavelength verification in laboratory and production settings; HeNe-referenced calibration checks via push-button calibration; tunable laser monitoring with RS-232 automation; spectroscopy and metrology wavelength reference at bench level; legacy Burleigh wavemeter system maintenance. Calibration: HeNe push-button calibration Related Model: WA-2500 (400 to 1800 nm extended coverage—separate instrument) Provide adequate input power for reliable fringe counting per unit faceplate. Perform HeNe calibration per manufacturer procedure when reference drift is suspected. Confirm installed detector configuration before quoting wavelength coverage. Do not assume WA-2000 shares the WA-2500 400 to 1800 nm specification—the WA-2500 is the VIS/NIR/IR extended-range Wavemeter Jr variant. Confirm detector options and rated wavelength span on the specific WA-2000 faceplate rather than copying WA-2500 limits. Alias WA2000.



MODEL

**Burleigh WA-2000**

CALIBRATION

**Available on request**

CONDITION

**Used**

STATUS

**In stock**

RFQ / SKU

**WA-2000**

LISTING

<https://aumictechlabs.com/products/wa-2000-2/>

NIST-traceable cal

SAM registered

30-day returns

NAICS 423690 • 811210 • 541380

**This unit**

The Burleigh WA-2000 Wavemeter Junior is a compact, cost-effective instrument for precise laser wavelength measurement using Michelson interferometer technology. It delivers absolute wavelength measurements across the UV-to-near-infrared spectrum with high accuracy and resolution. The unit features an intuitive digital interface and durable construction suitable for research laboratories and industrial environments. A collimated laser beam input couples to the optical engine, with wavelength values displayed on an integrated digital readout. Serial communication ports enable data logging and remote system integration.

**Technical Specifications**  
Wavelength Range: 400 nm to 1800 nm Accuracy:  $\pm 0.02 \text{ cm}^{-1}$  Resolution: 0.001 nm Measurement Type: Absolute wavelength Technology: Michelson Interferometer Input: Collimated laser beam Output: Digital display; serial data output (RS-232) Power: Standard AC input

**Key Features**  
Compact form factor for benchtop or rack-mount deployment Lightweight design for transport and placement flexibility Real-time wavelength readings via integrated digital display Minimal control panel with power, measurement, and configuration functions Serial interface for automated measurement logging and system control

**Typical Applications**  
Laser wavelength characterization in spectroscopy Production line wavelength verification Research applications requiring absolute wavelength measurement Industrial quality assurance and process monitoring

**Compatibility & Integration**  
The WA-2000 Junior accepts collimated beams from laser sources operating within its 400–1800 nm range. Beam quality, power level, and collimation directly influence measurement performance. Instruments equipped with serial communication support integration into automated measurement systems and external data logging platforms.

## Features & description

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From manufacturer datasheet

### Features

- Wavemeter Junior Michelson fringe-count architecture • HeNe push-button calibration • LED wavelength display • RS-232 remote interface • Typical visible (VIS) class wavelength coverage • Distinct from WA-2500 VIS/NIR/IR extended-range model

# WA2000 Characteristics / Specifications

| PARAMETER             | VALUE                                                                                                                                                                                                                                                                                  |
|-----------------------|----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| Model                 | WA-2000 (WA2000)                                                                                                                                                                                                                                                                       |
| Manufacturer          | Burleigh                                                                                                                                                                                                                                                                               |
| Instrument Type       | Laser Wavelength Meter (Wavemeter Junior)                                                                                                                                                                                                                                              |
| Measurement Principle | Michelson fringe counting                                                                                                                                                                                                                                                              |
| Laser Type            | CW                                                                                                                                                                                                                                                                                     |
| Wavelength Coverage   | Typical VIS class—confirm detector options on unit                                                                                                                                                                                                                                     |
| Calibration           | HeNe push-button calibration                                                                                                                                                                                                                                                           |
| Display               | LED                                                                                                                                                                                                                                                                                    |
| Remote Interface      | RS-232                                                                                                                                                                                                                                                                                 |
| Related Model         | WA-2500 (400 to 1800 nm extended coverage—separate instrument)                                                                                                                                                                                                                         |
| Alias                 | WA2000 Standard Operating Conditions Provide adequate input power for reliable fringe counting per unit faceplate. Perform HeNe calibration per manufacturer procedure when reference drift is suspected. Confirm installed detector configuration before quoting wavelength coverage. |

# Full OEM specifications

Complete technical content extracted from the manufacturer datasheet. Sparse OEM tables are reconstructed as tables below; other text is preserved as paragraphs.

Specifications

Specifications

| PARAMETER             | VALUE                                                          |
|-----------------------|----------------------------------------------------------------|
| Model                 | WA-2000 (WA2000)                                               |
| Manufacturer          | Burleigh                                                       |
| Instrument Type       | Laser Wavelength Meter (Wavemeter Junior)                      |
| Measurement Principle | Michelson fringe counting                                      |
| Laser Type            | CW                                                             |
| Wavelength Coverage   | Typical VIS class-confirm detector options on unit             |
| Calibration           | HeNe push-button calibration                                   |
| Display               | LED                                                            |
| Remote Interface      | RS-232                                                         |
| Related Model         | WA-2500 (400 to 1800 nm extended coverage-separate instrument) |
| Alias                 | WA2000                                                         |

Standard Operating Conditions

Provide adequate input power for reliable fringe counting per unit faceplate. Perform HeNe calibration per manufacturer procedure when reference drift is suspected. Confirm installed detector configuration before quoting wavelength coverage.

Operational Notes

Do not assume WA-2000 shares the WA-2500 400 to 1800 nm specification-the WA-2500 is the VIS/NIR/IR extended-range Wavemeter Jr variant. Confirm detector options and rated wavelength span on the specific WA-2000 faceplate rather than copying WA-2500 limits. Alias WA2000.

### Available from Aumictech

Used and refurbished unit evaluated in-house. Calibration: Available on request. Used · In stock.

Request a quote: [sales@aumictech.com](mailto:sales@aumictech.com) · +1 (484) 841-9341

#### Aumictech

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Technical content from manufacturer specifications. Unit photo/stock from Aumictech listing when available. Specifications subject to OEM documentation and unit condition.